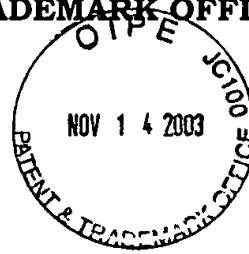


IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. N . : 09/742,224
Applicant : Walx FANG ET AL
Filed : December 22, 2000
Title : METHOD FOR DETERMINING FAILURE RATE
AND SELECTING BEST BURN-IN TIME
TC/A.U. : 2857
Examiner : Baran, Mary C
Docket No. : 4425-102



Honorable Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

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AMENDMENT

Sir:

In response to the Official Action mailed August 14, 2003. Preliminary to examining this application Applicants respectfully request that the Examiner reconsider the amended application according to the following remarks.

Please amend the above-identified application as follows: